



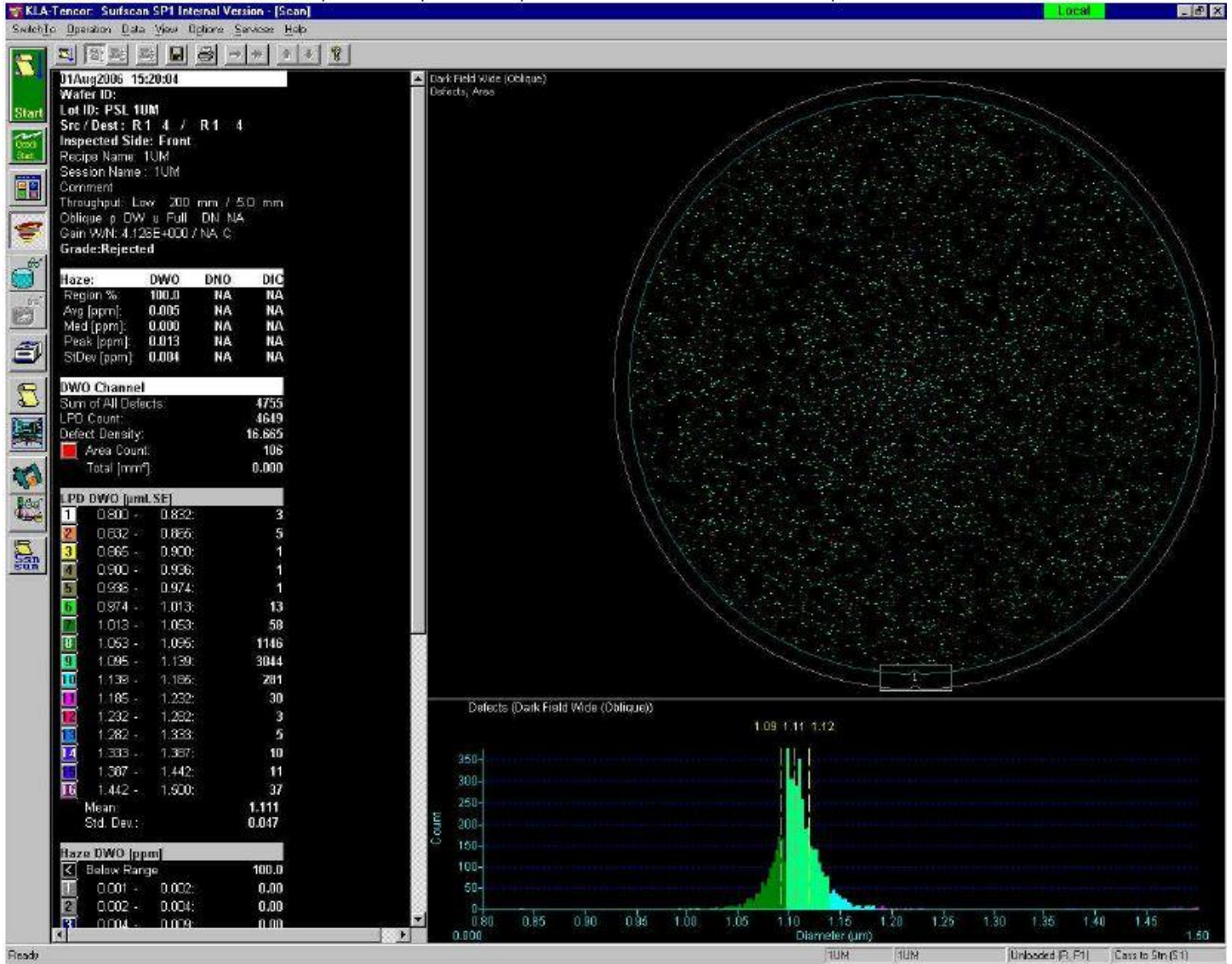
PSL 晶片校准标准: 80nm到3.040μm

污点堆积从 80nm 到 1.112μm

全部堆积: 80nm 到 3.04μm

PSL和NIST SRM粒子尺寸标准

100mm, 150mm, 150mm, 200mm 和 300mm 晶片, 初级Si



PSL晶片校准标准包括:

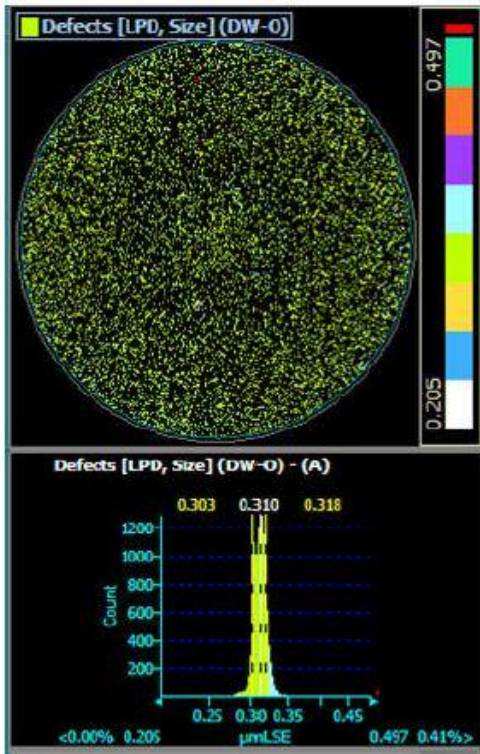
- 1) NIST可追踪的PSL尺寸证书以NIST SRM尺寸校准为基础
- 2) 给SP1上放置的晶片扫描提供了颜色打印输出和PSL尺寸证书
- 3) 包裹在单晶圆载体内, 装入袋中在运输过程中保持清洁
- 4) 每个晶片的标准, 单晶圆载体都标注有堆积放置的说明
- 5) NIST SRM 101.8nm,269nm和895nm尺寸也有效

代理商

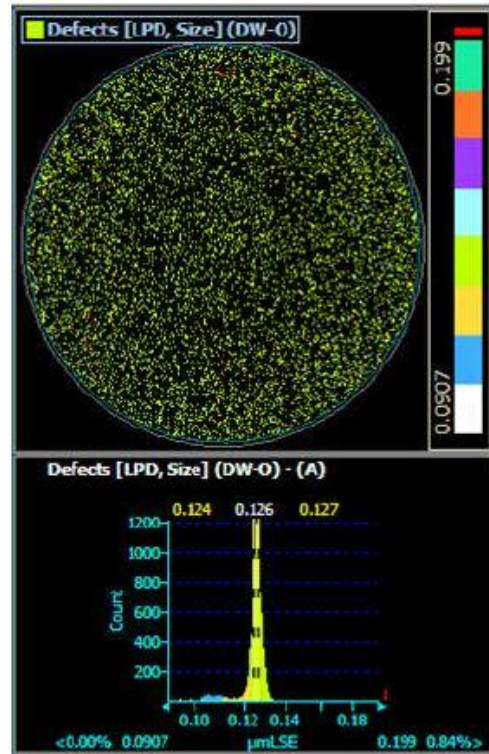


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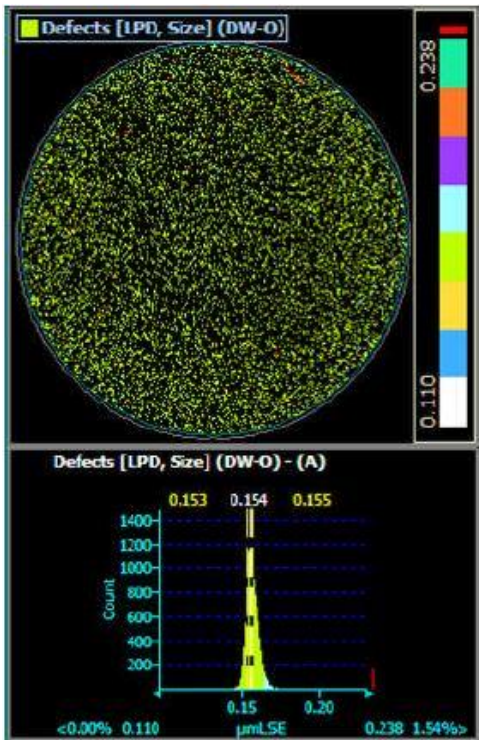


SSIS校准304nm

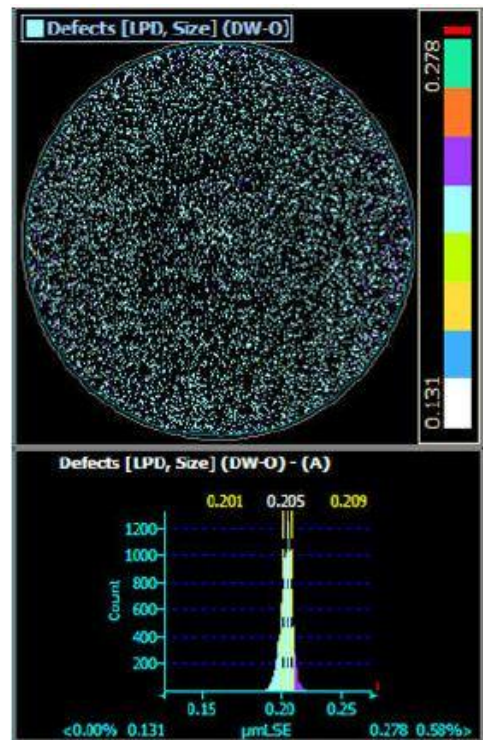


SSIS需要校准126nm

污点和所有晶片PSL堆积



SSIS校准接近155nm



SSIS校准接近@ 204nm

SPOT and FULL WAFER PSL DEPOSITIONS